

Search Notes

Application/Control No.

10/533,888

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

KAWASE ET AL.

Art Unit

1792

SEARCHED

Class	Subclass	Date	Examiner
252	79.1	10/7/2008	BT
252	79.4	10/7/2008	BT
252	79.5	10/7/2008	BT
438	692	10/7/2008	BT
438	693	10/7/2008	BT

INTERFERENCE SEARCHED

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252	79.1	10/7/2008	BT
252	79.4	10/7/2008	BT
252	79.5	10/07/2008	BT
438/692 438/693		10/7/2008	BT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using databases in EAST	10/7/2008	BT